TID Report

TI Part Number	UC19432-SP
Device Function	Rad-Tolerant Class-V, Precision Analog Controller
Package	8 JG
Technology	Bipolar
Die Lot Number	0103971SHE
A/T Lot Number / Date Code	0347969MMT(LTC: 1051A), 0347968MMT(LTC: 1051B)
Quantity Tested	22 device including 2 control device. 10 devices per radiation dose rate.
Lot Accept/Reject	Devices passed 20krad(Si) and 30krad(Si)
Radiation Facility	Radiation Assured Devices Longmire Laboratories, Colorado Springs, CO
Total Dose	20krad(Si) and 30krad(Si)
Total Dose Rate	10 mrad(Si)/sec
Radiation Source	GB-150 Co-60
Irradiation Temperature	Ambient, room temperature

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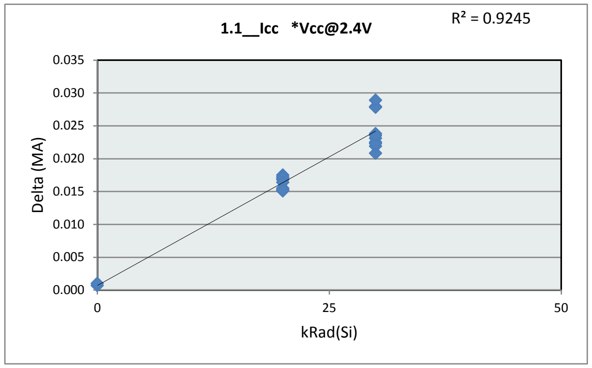
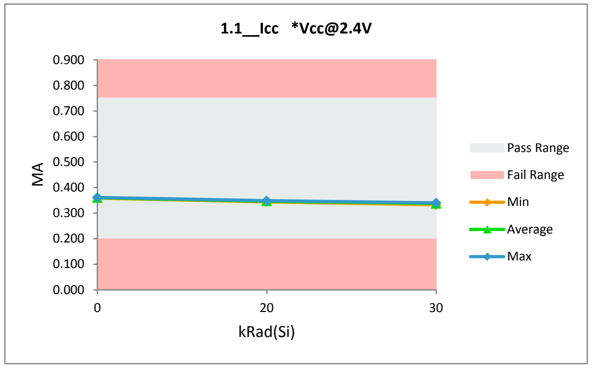
		1.1__Icc *Vcc@2.4V		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MA	MA	
	Max Limit	0.75	0.75	
	Min Limit	0.2	0.2	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.362	0.361	0.001
0	L3_D84_Corr	0.360	0.359	0.001
20	L3_D11_Bias	0.361	0.345	0.017
20	L3_D12_Bias	0.366	0.349	0.017
20	L3_D13_Bias	0.364	0.348	0.017
20	L3_D14_Bias	0.364	0.347	0.017
20	L3_D15_Bias	0.362	0.345	0.017
20	L4_D16_Bias	0.361	0.345	0.016
20	L4_D17_Bias	0.364	0.349	0.015
20	L4_D18_Bias	0.362	0.347	0.015
20	L4_D19_Bias	0.362	0.346	0.016
20	L4_D20_Bias	0.363	0.348	0.015
30	L3_D31_Bias	0.360	0.332	0.028
30	L3_D32_Bias	0.359	0.335	0.024
30	L3_D33_Bias	0.362	0.340	0.023
30	L3_D34_Bias	0.366	0.338	0.028
30	L3_D35_Bias	0.366	0.337	0.029
30	L4_D36_Bias	0.361	0.340	0.021
30	L4_D37_Bias	0.359	0.336	0.023
30	L4_D38_Bias	0.361	0.339	0.022
30	L4_D39_Bias	0.363	0.341	0.022
30	L4_D40_Bias	0.363	0.339	0.024
	Max	0.366	0.361	0.029
	Average	0.362	0.344	0.019
	Min	0.359	0.332	0.001
	Std Dev	0.002	0.007	0.007



	1.1__Icc *Vcc@2.4V		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.75	MA	
Min Limit	0.2	MA	
kRad(Si)	0	20	30
LL	0.200	0.200	0.200
Min	0.359	0.345	0.332
Average	0.360	0.347	0.338
Max	0.361	0.349	0.341
UL	0.750	0.750	0.750



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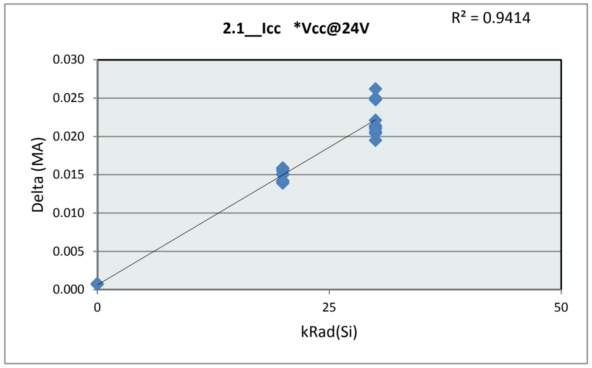
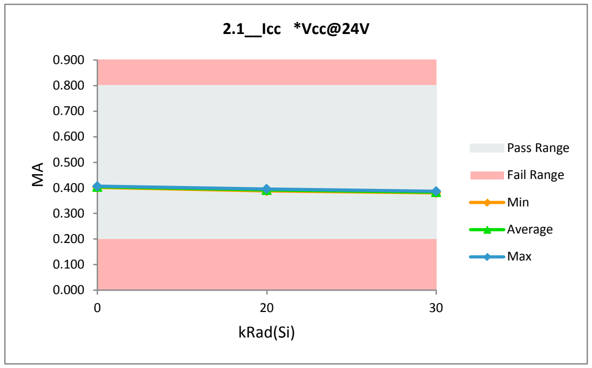
	2.1__Icc *Vcc@24V	
Test Site	Sherman TX	Sherman TX
Tester	Eagle	Eagle
Test Number	EF266101	EF266101
Unit	MA	MA
Max Limit	0.8	0.8
Min Limit	0.2	0.2

kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.407	0.406	0.001
0	L3_D84_Corr	0.402	0.401	0.001
20	L3_D11_Bias	0.407	0.391	0.015
20	L3_D12_Bias	0.412	0.396	0.016
20	L3_D13_Bias	0.410	0.395	0.016
20	L3_D14_Bias	0.410	0.394	0.016
20	L3_D15_Bias	0.407	0.391	0.016
20	L4_D16_Bias	0.403	0.388	0.015
20	L4_D17_Bias	0.408	0.394	0.014
20	L4_D18_Bias	0.404	0.390	0.014
20	L4_D19_Bias	0.404	0.390	0.014
20	L4_D20_Bias	0.406	0.392	0.014
30	L3_D31_Bias	0.405	0.380	0.025
30	L3_D32_Bias	0.404	0.382	0.021
30	L3_D33_Bias	0.407	0.387	0.021
30	L3_D34_Bias	0.412	0.387	0.025
30	L3_D35_Bias	0.411	0.385	0.026
30	L4_D36_Bias	0.404	0.384	0.019
30	L4_D37_Bias	0.402	0.381	0.021
30	L4_D38_Bias	0.403	0.382	0.020
30	L4_D39_Bias	0.405	0.384	0.021
30	L4_D40_Bias	0.405	0.383	0.022
	Max	0.412	0.406	0.026
	Average	0.406	0.389	0.017
	Min	0.402	0.380	0.001
	Std Dev	0.003	0.007	0.007



	2.1__Icc *Vcc@24V		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.8	MA	
Min Limit	0.2	MA	
kRad(Si)	0	20	30
LL	0.200	0.200	0.200
Min	0.401	0.388	0.380
Average	0.404	0.392	0.384
Max	0.406	0.396	0.387
UL	0.800	0.800	0.800



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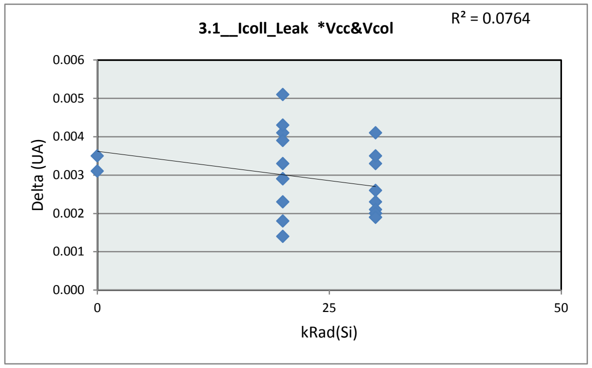
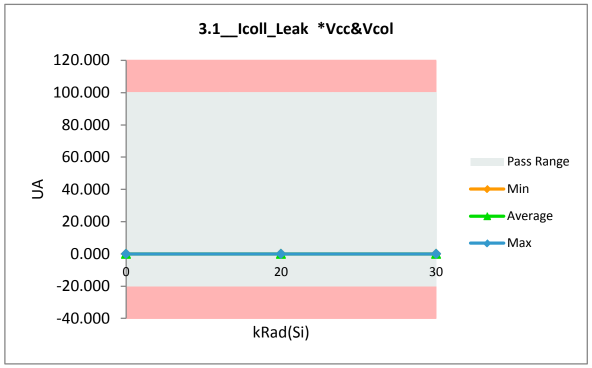
	3.1__Icoll_Leak *Vcc&Vcol		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	UA	UA	
	Max Limit	100	100	
	Min Limit	-20	-20	

kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.024	0.021	0.003
0	L3_D84_Corr	0.020	0.016	0.003
20	L3_D11_Bias	0.024	0.019	0.005
20	L3_D12_Bias	0.020	0.017	0.003
20	L3_D13_Bias	0.022	0.020	0.002
20	L3_D14_Bias	0.018	0.017	0.001
20	L3_D15_Bias	0.024	0.020	0.004
20	L4_D16_Bias	0.020	0.015	0.004
20	L4_D17_Bias	0.024	0.020	0.004
20	L4_D18_Bias	0.021	0.018	0.003
20	L4_D19_Bias	0.020	0.017	0.002
20	L4_D20_Bias	0.023	0.020	0.003
30	L3_D31_Bias	0.020	0.016	0.004
30	L3_D32_Bias	0.021	0.018	0.003
30	L3_D33_Bias	0.025	0.023	0.002
30	L3_D34_Bias	0.020	0.018	0.002
30	L3_D35_Bias	0.020	0.018	0.002
30	L4_D36_Bias	0.021	0.018	0.003
30	L4_D37_Bias	0.019	0.016	0.003
30	L4_D38_Bias	0.019	0.017	0.002
30	L4_D39_Bias	0.019	0.016	0.002
30	L4_D40_Bias	0.019	0.017	0.002
	Max	0.025	0.023	0.005
	Average	0.021	0.018	0.003
	Min	0.018	0.015	0.001
	Std Dev	0.002	0.002	0.001



	3.1__Icoll_Leak *Vcc&Vcol		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	100	UA	
Min Limit	-20	UA	
kRad(Si)	0	20	30
LL	-20.000	-20.000	-20.000
Min	0.016	0.016	0.016
Average	0.019	0.018	0.018
Max	0.021	0.020	0.023
UL	100.000	100.000	100.000



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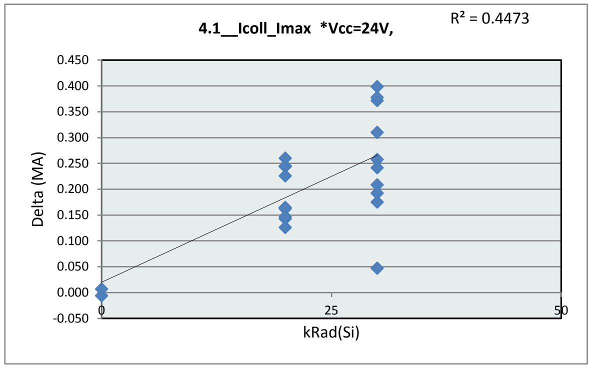
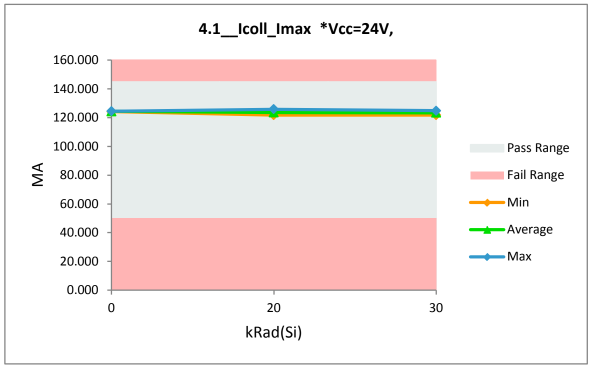
		4.1__Icoll_Imax *Vcc=24V,		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MA	MA	
	Max Limit	145	145	
	Min Limit	50	50	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	124.549	124.555	-0.006
0	L3_D84_Corr	124.209	124.202	0.007
20	L3_D11_Bias	122.081	121.837	0.245
20	L3_D12_Bias	123.584	123.340	0.244
20	L3_D13_Bias	124.875	124.630	0.245
20	L3_D14_Bias	124.195	123.935	0.260
20	L3_D15_Bias	126.132	125.907	0.226
20	L4_D16_Bias	124.275	124.111	0.164
20	L4_D17_Bias	123.167	123.005	0.162
20	L4_D18_Bias	122.614	122.471	0.143
20	L4_D19_Bias	123.935	123.809	0.126
20	L4_D20_Bias	123.831	123.685	0.147
30	L3_D31_Bias	123.113	122.714	0.398
30	L3_D32_Bias	122.051	121.794	0.257
30	L3_D33_Bias	125.074	124.865	0.208
30	L3_D34_Bias	123.623	123.313	0.310
30	L3_D35_Bias	123.664	123.293	0.371
30	L4_D36_Bias	123.573	123.526	0.047
30	L4_D37_Bias	123.577	123.335	0.241
30	L4_D38_Bias	123.232	123.058	0.175
30	L4_D39_Bias	124.804	124.612	0.192
30	L4_D40_Bias	124.666	124.288	0.377
	Max	126.132	125.907	0.398
	Average	123.856	123.649	0.206
	Min	122.051	121.794	-0.006
	Std Dev	0.972	0.989	0.108



	4.1__Icoll_Imax *Vcc=24V,		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	145	MA	
Min Limit	50	MA	
kRad(Si)	0	20	30
LL	50.000	50.000	50.000
Min	124.202	121.837	121.794
Average	124.379	123.673	123.480
Max	124.555	125.907	124.865
UL	145.000	145.000	145.000



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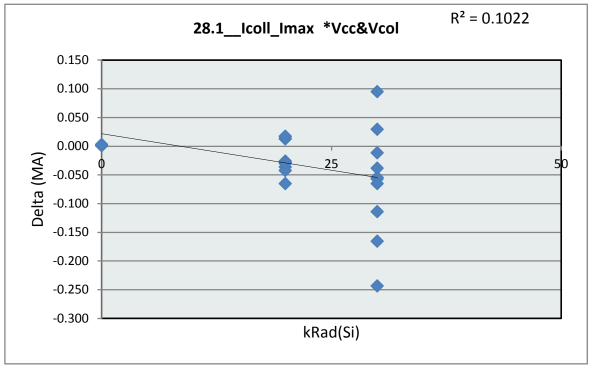
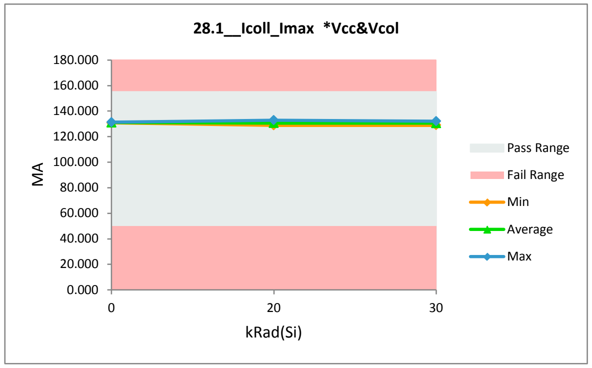
		28.1__Icoll_Imax *Vcc&Vcol		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MA	MA	
	Max Limit	155	155	
	Min Limit	50	50	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	131.330	131.329	0.001
0	L3_D84_Corr	130.773	130.771	0.003
20	L3_D11_Bias	128.791	128.778	0.013
20	L3_D12_Bias	130.371	130.358	0.013
20	L3_D13_Bias	131.814	131.797	0.017
20	L3_D14_Bias	130.960	130.943	0.017
20	L3_D15_Bias	132.908	132.944	-0.036
20	L4_D16_Bias	130.880	130.906	-0.026
20	L4_D17_Bias	129.757	129.786	-0.028
20	L4_D18_Bias	129.269	129.334	-0.065
20	L4_D19_Bias	130.523	130.566	-0.043
20	L4_D20_Bias	130.465	130.496	-0.030
30	L3_D31_Bias	129.839	129.810	0.029
30	L3_D32_Bias	128.885	128.942	-0.057
30	L3_D33_Bias	131.925	132.090	-0.165
30	L3_D34_Bias	130.527	130.582	-0.055
30	L3_D35_Bias	130.482	130.494	-0.012
30	L4_D36_Bias	130.201	130.444	-0.244
30	L4_D37_Bias	130.020	130.059	-0.038
30	L4_D38_Bias	129.655	129.769	-0.114
30	L4_D39_Bias	131.420	131.485	-0.065
30	L4_D40_Bias	131.227	131.132	0.095
	Max	132.908	132.944	0.095
	Average	130.546	130.582	-0.036
	Min	128.791	128.778	-0.244
	Std Dev	1.002	1.001	0.070



	28.1__Icoll_Imax *Vcc&Vcol		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	155	MA	
Min Limit	50	MA	
kRad(Si)	0	20	30
LL	50.000	50.000	50.000
Min	130.771	128.778	128.942
Average	131.050	130.591	130.481
Max	131.329	132.944	132.090
UL	155.000	155.000	155.000



TID Report
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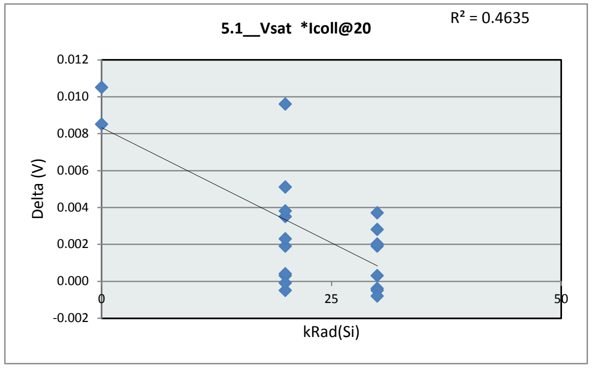
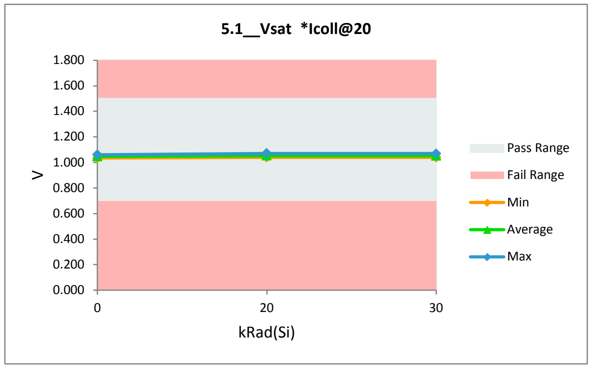
		5.1__Vsat *Icoll@20		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	V	V	
	Max Limit	1.5	1.5	
	Min Limit	0.7	0.7	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	1.072	1.061	0.010
0	L3_D84_Corr	1.044	1.035	0.008
20	L3_D11_Bias	1.073	1.071	0.002
20	L3_D12_Bias	1.060	1.057	0.003
20	L3_D13_Bias	1.061	1.061	0.000
20	L3_D14_Bias	1.056	1.052	0.004
20	L3_D15_Bias	1.063	1.053	0.010
20	L4_D16_Bias	1.039	1.040	-0.001
20	L4_D17_Bias	1.058	1.053	0.005
20	L4_D18_Bias	1.053	1.053	0.000
20	L4_D19_Bias	1.046	1.046	0.000
20	L4_D20_Bias	1.052	1.049	0.002
30	L3_D31_Bias	1.061	1.059	0.003
30	L3_D32_Bias	1.073	1.069	0.004
30	L3_D33_Bias	1.064	1.061	0.002
30	L3_D34_Bias	1.064	1.062	0.002
30	L3_D35_Bias	1.060	1.060	0.000
30	L4_D36_Bias	1.052	1.050	0.002
30	L4_D37_Bias	1.043	1.042	0.000
30	L4_D38_Bias	1.043	1.041	0.002
30	L4_D39_Bias	1.040	1.040	0.000
30	L4_D40_Bias	1.045	1.046	-0.001
	Max	1.073	1.071	0.010
	Average	1.056	1.053	0.003
	Min	1.039	1.035	-0.001
	Std Dev	0.011	0.010	0.003



	5.1__Vsat *Icoll@20		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	1.5	V	
Min Limit	0.7	V	
kRad(Si)	0	20	30
LL	0.700	0.700	0.700
Min	1.035	1.040	1.040
Average	1.048	1.054	1.053
Max	1.061	1.072	1.069
UL	1.500	1.500	1.500



TID Report
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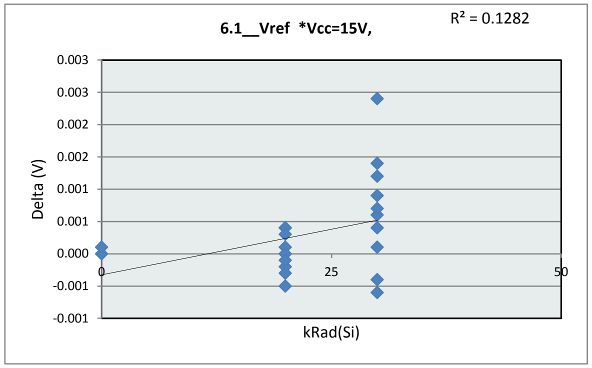
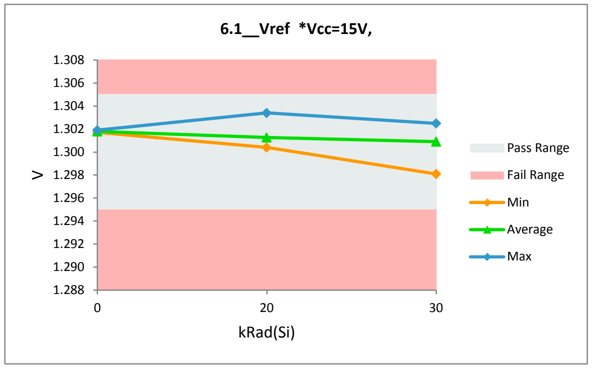
		6.1__Vref *Vcc=15V,		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	V	V	
	Max Limit	1.305	1.305	
	Min Limit	1.295	1.295	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	1.302	1.302	0.000
0	L3_D84_Corr	1.302	1.302	0.000
20	L3_D11_Bias	1.301	1.301	0.000
20	L3_D12_Bias	1.302	1.301	0.000
20	L3_D13_Bias	1.301	1.300	0.000
20	L3_D14_Bias	1.301	1.301	0.000
20	L3_D15_Bias	1.302	1.302	0.000
20	L4_D16_Bias	1.301	1.300	0.000
20	L4_D17_Bias	1.300	1.301	0.000
20	L4_D18_Bias	1.301	1.301	0.000
20	L4_D19_Bias	1.302	1.302	0.000
20	L4_D20_Bias	1.303	1.303	0.000
30	L3_D31_Bias	1.301	1.298	0.002
30	L3_D32_Bias	1.301	1.301	0.001
30	L3_D33_Bias	1.302	1.302	-0.001
30	L3_D34_Bias	1.302	1.301	0.001
30	L3_D35_Bias	1.303	1.301	0.001
30	L4_D36_Bias	1.302	1.303	0.000
30	L4_D37_Bias	1.301	1.300	0.001
30	L4_D38_Bias	1.301	1.301	0.000
30	L4_D39_Bias	1.301	1.301	0.000
30	L4_D40_Bias	1.302	1.301	0.001
	Max	1.303	1.303	0.002
	Average	1.301	1.301	0.000
	Min	1.300	1.298	-0.001
	Std Dev	0.001	0.001	0.001

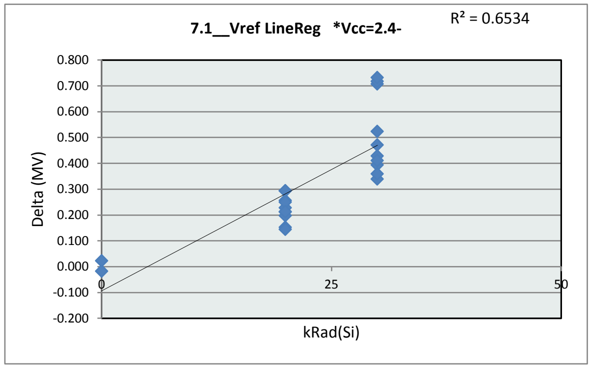


	6.1__Vref *Vcc=15V,		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	1.305	V	
Min Limit	1.295	V	
kRad(Si)	0	20	30
LL	1.295	1.295	1.295
Min	1.302	1.300	1.298
Average	1.302	1.301	1.301
Max	1.302	1.303	1.303
UL	1.305	1.305	1.305

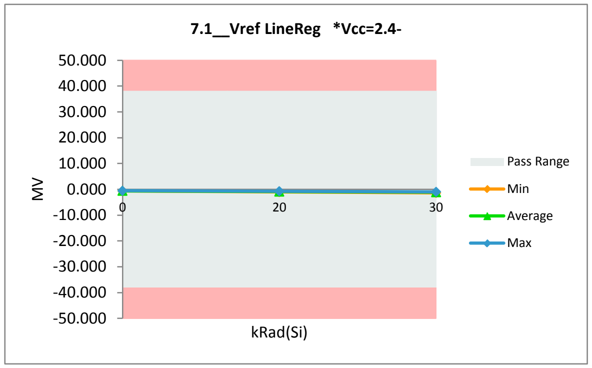


TID Report
UC19432-SP

		7.1__Vref LineReg *Vcc=2.4-		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MV	MV	
	Max Limit	38	38	
	Min Limit	-38	-38	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	-0.673	-0.656	-0.017
0	L3_D84_Corr	-0.508	-0.530	0.023
20	L3_D11_Bias	-0.732	-0.960	0.229
20	L3_D12_Bias	-0.710	-1.003	0.293
20	L3_D13_Bias	-0.718	-0.930	0.212
20	L3_D14_Bias	-0.601	-0.895	0.294
20	L3_D15_Bias	-0.621	-0.878	0.256
20	L4_D16_Bias	-0.530	-0.780	0.250
20	L4_D17_Bias	-0.584	-0.736	0.153
20	L4_D18_Bias	-0.579	-0.776	0.197
20	L4_D19_Bias	-0.663	-0.876	0.213
20	L4_D20_Bias	-0.668	-0.813	0.144
30	L3_D31_Bias	-0.562	-1.269	0.707
30	L3_D32_Bias	-0.556	-1.079	0.524
30	L3_D33_Bias	-0.603	-1.075	0.471
30	L3_D34_Bias	-0.668	-1.386	0.718
30	L3_D35_Bias	-0.621	-1.353	0.732
30	L4_D36_Bias	-0.689	-1.028	0.339
30	L4_D37_Bias	-0.711	-1.105	0.394
30	L4_D38_Bias	-0.576	-1.005	0.429
30	L4_D39_Bias	-0.587	-0.998	0.411
30	L4_D40_Bias	-0.610	-0.969	0.359
	Max	-0.508	-0.530	0.732
	Average	-0.626	-0.959	0.333
	Min	-0.732	-1.386	-0.017
	Std Dev	0.064	0.210	0.205



	7.1__Vref LineReg *Vcc=2.4-		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	38	MV	
Min Limit	-38	MV	
kRad(Si)	0	20	30
LL	-38.000	-38.000	-38.000
Min	-0.656	-1.004	-1.386
Average	-0.593	-0.865	-1.127
Max	-0.531	-0.736	-0.969
UL	38.000	38.000	38.000



TID Report
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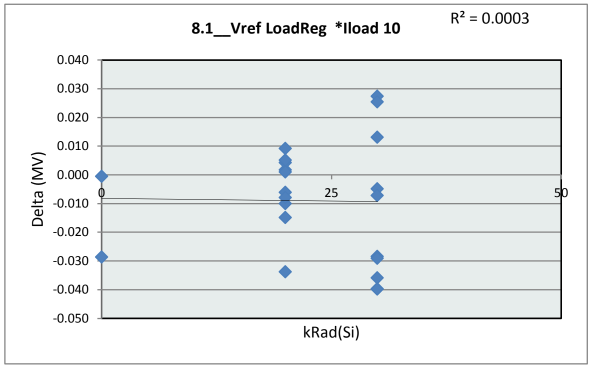
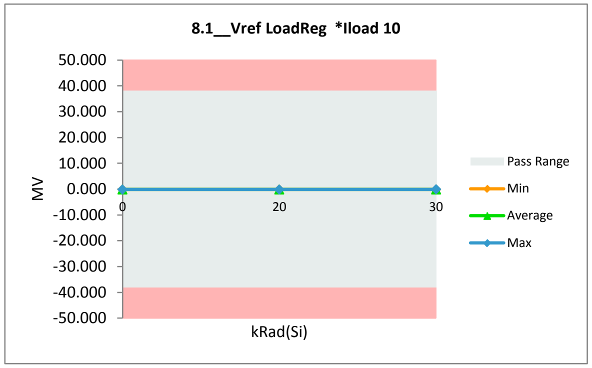
		8.1__Vref LoadReg *Iload 10		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MV	MV	
	Max Limit	38	38	
	Min Limit	-38	-38	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	-0.139	-0.139	0.000
0	L3_D84_Corr	-0.161	-0.133	-0.029
20	L3_D11_Bias	-0.136	-0.126	-0.010
20	L3_D12_Bias	-0.164	-0.131	-0.034
20	L3_D13_Bias	-0.121	-0.123	0.002
20	L3_D14_Bias	-0.128	-0.132	0.004
20	L3_D15_Bias	-0.125	-0.130	0.005
20	L4_D16_Bias	-0.163	-0.172	0.009
20	L4_D17_Bias	-0.147	-0.148	0.001
20	L4_D18_Bias	-0.169	-0.163	-0.006
20	L4_D19_Bias	-0.139	-0.131	-0.008
20	L4_D20_Bias	-0.155	-0.140	-0.015
30	L3_D31_Bias	-0.153	-0.114	-0.040
30	L3_D32_Bias	-0.138	-0.098	-0.040
30	L3_D33_Bias	-0.129	-0.157	0.027
30	L3_D34_Bias	-0.128	-0.123	-0.005
30	L3_D35_Bias	-0.138	-0.130	-0.007
30	L4_D36_Bias	-0.141	-0.155	0.013
30	L4_D37_Bias	-0.147	-0.172	0.025
30	L4_D38_Bias	-0.159	-0.130	-0.028
30	L4_D39_Bias	-0.176	-0.140	-0.036
30	L4_D40_Bias	-0.161	-0.132	-0.029
	Max	-0.121	-0.098	0.027
	Average	-0.146	-0.137	-0.009
	Min	-0.176	-0.172	-0.040
	Std Dev	0.016	0.018	0.020

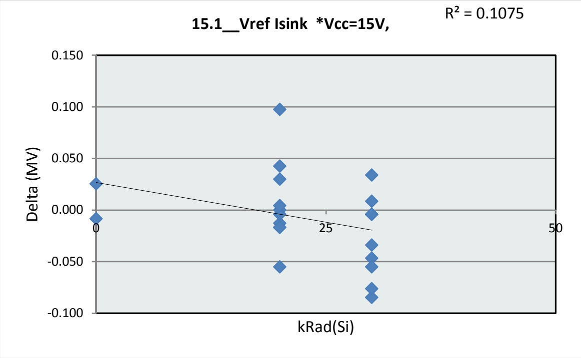


	8.1__Vref LoadReg *Iload 10		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	38	MV	
Min Limit	-38	MV	
kRad(Si)	0	20	30
LL	-38.000	-38.000	-38.000
Min	-0.139	-0.172	-0.172
Average	-0.136	-0.140	-0.135
Max	-0.133	-0.123	-0.099
UL	38.000	38.000	38.000

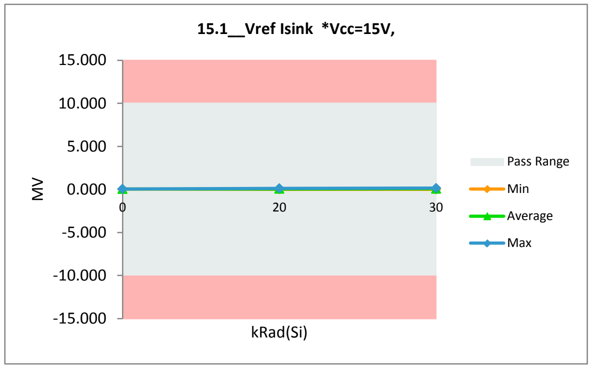


TID Report
UC19432-SP

		15.1__Vref Isink *Vcc=15V,		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MV	MV	
	Max Limit	10	10	
	Min Limit	-10	-10	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.055	0.064	-0.009
0	L3_D84_Corr	0.055	0.030	0.025
20	L3_D11_Bias	0.068	0.025	0.042
20	L3_D12_Bias	0.055	0.072	-0.017
20	L3_D13_Bias	0.059	0.115	-0.055
20	L3_D14_Bias	0.127	0.030	0.098
20	L3_D15_Bias	0.085	0.085	0.000
20	L4_D16_Bias	0.047	0.059	-0.013
20	L4_D17_Bias	0.047	0.051	-0.004
20	L4_D18_Bias	0.102	0.072	0.030
20	L4_D19_Bias	0.051	0.068	-0.017
20	L4_D20_Bias	0.076	0.072	0.004
30	L3_D31_Bias	0.089	0.123	-0.034
30	L3_D32_Bias	0.047	0.051	-0.004
30	L3_D33_Bias	0.047	0.093	-0.047
30	L3_D34_Bias	0.081	0.085	-0.004
30	L3_D35_Bias	0.059	0.144	-0.085
30	L4_D36_Bias	0.081	0.072	0.009
30	L4_D37_Bias	0.009	0.013	-0.004
30	L4_D38_Bias	0.106	0.072	0.034
30	L4_D39_Bias	0.017	0.072	-0.055
30	L4_D40_Bias	0.013	0.089	-0.076
	Max	0.127	0.144	0.098
	Average	0.062	0.071	-0.008
	Min	0.009	0.013	-0.085
	Std Dev	0.030	0.032	0.041



	15.1__Vref Isink *Vcc=15V,		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	10	MV	
Min Limit	-10	MV	
kRad(Si)	0	20	30
LL	-10.000	-10.000	-10.000
Min	0.030	0.025	0.013
Average	0.047	0.065	0.081
Max	0.064	0.115	0.144
UL	10.000	10.000	10.000



TID Report
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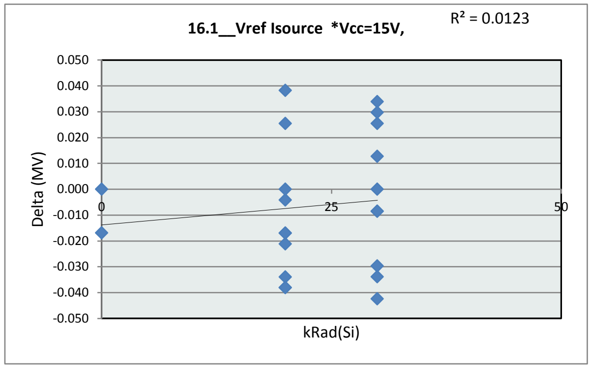
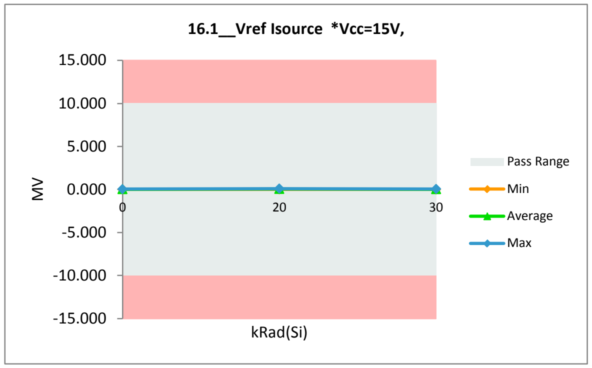
	16.1__Vref Isource *Vcc=15V,	
Test Site	Sherman TX	Sherman TX
Tester	Eagle	Eagle
Test Number	EF266101	EF266101
Unit	MV	MV
Max Limit	10	10
Min Limit	-10	-10

kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.013	0.013	0.000
0	L3_D84_Corr	0.017	0.034	-0.017
20	L3_D11_Bias	0.009	0.013	-0.004
20	L3_D12_Bias	0.059	0.021	0.038
20	L3_D13_Bias	0.051	0.089	-0.038
20	L3_D14_Bias	0.004	0.025	-0.021
20	L3_D15_Bias	0.068	0.042	0.025
20	L4_D16_Bias	0.025	0.042	-0.017
20	L4_D17_Bias	0.004	0.038	-0.034
20	L4_D18_Bias	0.064	0.081	-0.017
20	L4_D19_Bias	0.017	0.055	-0.038
20	L4_D20_Bias	0.047	0.047	0.000
30	L3_D31_Bias	0.055	0.021	0.034
30	L3_D32_Bias	0.064	0.038	0.025
30	L3_D33_Bias	0.004	0.047	-0.042
30	L3_D34_Bias	0.000	0.030	-0.030
30	L3_D35_Bias	0.017	0.051	-0.034
30	L4_D36_Bias	0.025	0.034	-0.009
30	L4_D37_Bias	0.038	0.009	0.030
30	L4_D38_Bias	0.021	0.030	-0.009
30	L4_D39_Bias	0.021	0.021	0.000
30	L4_D40_Bias	0.034	0.021	0.013
	Max	0.068	0.089	0.038
	Average	0.030	0.036	-0.007
	Min	0.000	0.009	-0.042
	Std Dev	0.022	0.020	0.025



	16.1__Vref Isource *Vcc=15V	
Test Site	Sherman TX	
Tester	Eagle	
Test Number	EF266101	
Max Limit	10	MV
Min Limit	-10	MV

kRad(Si)	0	20	30
LL	-10.000	-10.000	-10.000
Min	0.013	0.013	0.009
Average	0.023	0.045	0.030
Max	0.034	0.089	0.051
UL	10.000	10.000	10.000



TID Report
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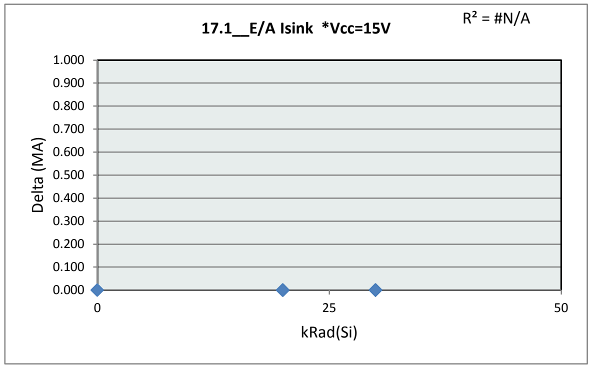
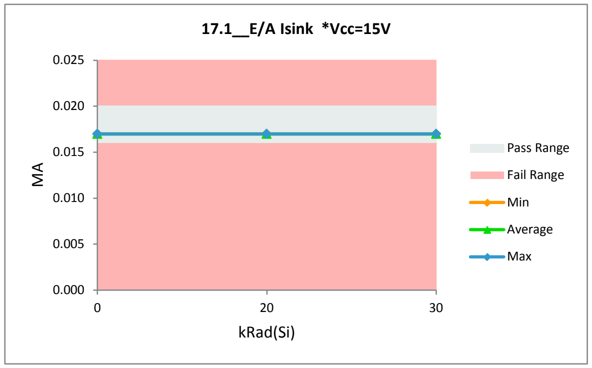
		17.1__E/A Isink *Vcc=15V		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MA	MA	
	Max Limit	0.02	0.02	
	Min Limit	0.016	0.016	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.017	0.017	0.000
0	L3_D84_Corr	0.017	0.017	0.000
20	L3_D11_Bias	0.017	0.017	0.000
20	L3_D12_Bias	0.017	0.017	0.000
20	L3_D13_Bias	0.017	0.017	0.000
20	L3_D14_Bias	0.017	0.017	0.000
20	L3_D15_Bias	0.017	0.017	0.000
20	L4_D16_Bias	0.017	0.017	0.000
20	L4_D17_Bias	0.017	0.017	0.000
20	L4_D18_Bias	0.017	0.017	0.000
20	L4_D19_Bias	0.017	0.017	0.000
20	L4_D20_Bias	0.017	0.017	0.000
30	L3_D31_Bias	0.017	0.017	0.000
30	L3_D32_Bias	0.017	0.017	0.000
30	L3_D33_Bias	0.017	0.017	0.000
30	L3_D34_Bias	0.017	0.017	0.000
30	L3_D35_Bias	0.017	0.017	0.000
30	L4_D36_Bias	0.017	0.017	0.000
30	L4_D37_Bias	0.017	0.017	0.000
30	L4_D38_Bias	0.017	0.017	0.000
30	L4_D39_Bias	0.017	0.017	0.000
30	L4_D40_Bias	0.017	0.017	0.000
	Max	0.017	0.017	0.000
	Average	0.017	0.017	0.000
	Min	0.017	0.017	0.000
	Std Dev	0.000	0.000	0.000



	17.1__E/A Isink *Vcc=15V		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.02	MA	
Min Limit	0.016	MA	
kRad(Si)	0	20	30
LL	0.016	0.016	0.016
Min	0.017	0.017	0.017
Average	0.017	0.017	0.017
Max	0.017	0.017	0.017
UL	0.020	0.020	0.020



TID Report
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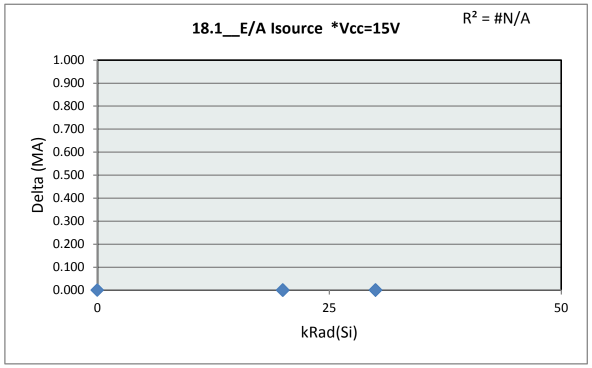
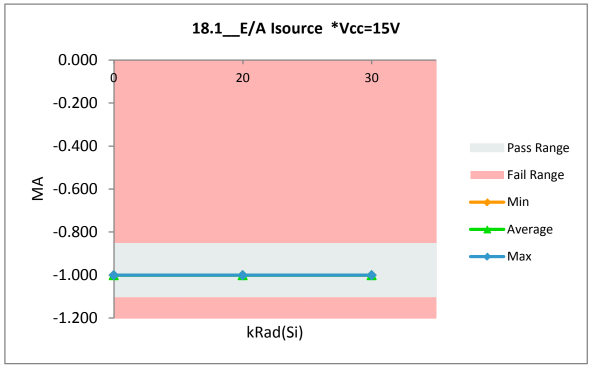
		18.1__E/A Isource *Vcc=15V		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MA	MA	
	Max Limit	-0.85	-0.85	
	Min Limit	-1.1	-1.1	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	-1.000	-1.000	0.000
0	L3_D84_Corr	-1.000	-1.000	0.000
20	L3_D11_Bias	-1.000	-1.000	0.000
20	L3_D12_Bias	-1.000	-1.000	0.000
20	L3_D13_Bias	-1.000	-1.000	0.000
20	L3_D14_Bias	-1.000	-1.000	0.000
20	L3_D15_Bias	-1.000	-1.000	0.000
20	L4_D16_Bias	-1.000	-1.000	0.000
20	L4_D17_Bias	-1.000	-1.000	0.000
20	L4_D18_Bias	-1.000	-1.000	0.000
20	L4_D19_Bias	-1.000	-1.000	0.000
20	L4_D20_Bias	-1.000	-1.000	0.000
30	L3_D31_Bias	-1.000	-1.000	0.000
30	L3_D32_Bias	-1.000	-1.000	0.000
30	L3_D33_Bias	-1.000	-1.000	0.000
30	L3_D34_Bias	-1.000	-1.000	0.000
30	L3_D35_Bias	-1.000	-1.000	0.000
30	L4_D36_Bias	-1.000	-1.000	0.000
30	L4_D37_Bias	-1.000	-1.000	0.000
30	L4_D38_Bias	-1.000	-1.000	0.000
30	L4_D39_Bias	-1.000	-1.000	0.000
30	L4_D40_Bias	-1.000	-1.000	0.000
	Max	-1.000	-1.000	0.000
	Average	-1.000	-1.000	0.000
	Min	-1.000	-1.000	0.000
	Std Dev	0.000	0.000	0.000



	18.1__E/A Isource *Vcc=15V		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	-0.85	MA	
Min Limit	-1.1	MA	
kRad(Si)	0	20	30
LL	-1.100	-1.100	-1.100
Min	-1.000	-1.000	-1.000
Average	-1.000	-1.000	-1.000
Max	-1.000	-1.000	-1.000
UL	-0.850	-0.850	-0.850



TID Report
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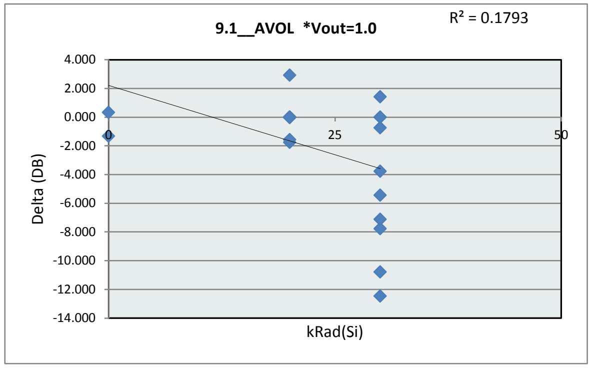
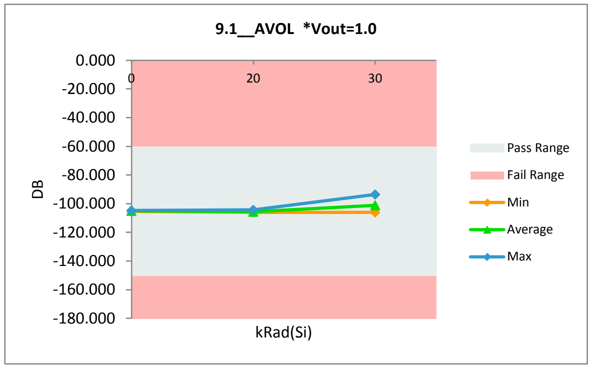
		9.1__AVOL *Vout=1.0		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	DB	DB	
	Max Limit	-60	-60	
	Min Limit	-150	-150	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	-105.022	-105.355	0.333
0	L3_D84_Corr	-106.021	-104.701	-1.319
20	L3_D11_Bias	-106.021	-105.988	-0.033
20	L3_D12_Bias	-106.021	-106.021	0.000
20	L3_D13_Bias	-106.021	-106.021	0.000
20	L3_D14_Bias	-106.021	-106.021	0.000
20	L3_D15_Bias	-106.021	-106.021	0.000
20	L4_D16_Bias	-106.021	-106.021	0.000
20	L4_D17_Bias	-106.021	-104.272	-1.749
20	L4_D18_Bias	-103.097	-106.021	2.924
20	L4_D19_Bias	-106.021	-106.021	0.000
20	L4_D20_Bias	-106.021	-104.453	-1.567
30	L3_D31_Bias	-106.021	-93.554	-12.466
30	L3_D32_Bias	-106.021	-98.251	-7.770
30	L3_D33_Bias	-106.021	-102.250	-3.771
30	L3_D34_Bias	-106.021	-95.243	-10.777
30	L3_D35_Bias	-106.021	-98.904	-7.117
30	L4_D36_Bias	-105.631	-100.189	-5.441
30	L4_D37_Bias	-106.021	-105.287	-0.733
30	L4_D38_Bias	-106.021	-106.021	0.000
30	L4_D39_Bias	-106.021	-106.021	0.000
30	L4_D40_Bias	-103.805	-105.220	1.415
	Max	-103.097	-93.554	2.924
	Average	-105.724	-103.539	-2.185
	Min	-106.021	-106.021	-12.466
	Std Dev	0.777	3.806	4.023



	9.1__AVOL *Vout=1.0		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	-60	DB	
Min Limit	-150	DB	
kRad(Si)	0	20	30
LL	-150.000	-150.000	-150.000
Min	-105.355	-106.021	-106.021
Average	-105.028	-105.686	-101.094
Max	-104.701	-104.272	-93.554
UL	-60.000	-60.000	-60.000



TID Report
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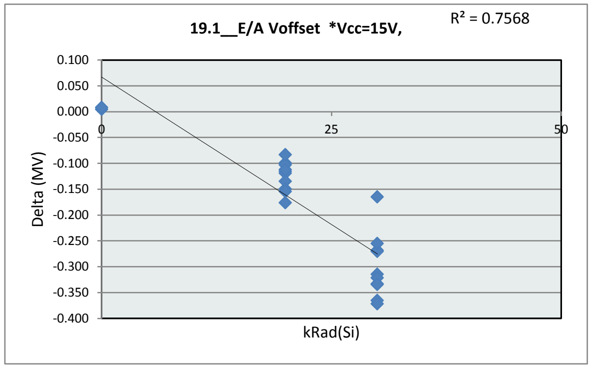
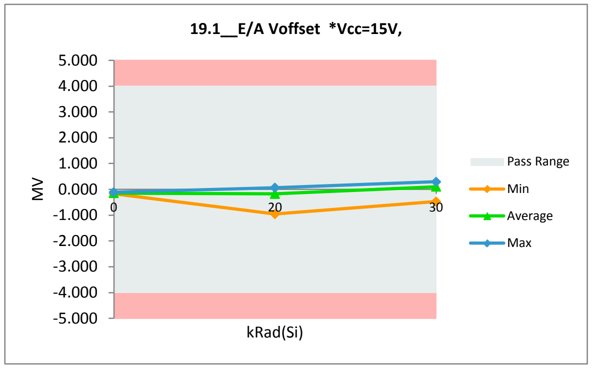
		19.1__E/A Voffset *Vcc=15V,		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MV	MV	
	Max Limit	4	4	
	Min Limit	-4	-4	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	-0.108	-0.112	0.005
0	L3_D84_Corr	-0.170	-0.178	0.008
20	L3_D11_Bias	-0.489	-0.373	-0.115
20	L3_D12_Bias	-0.057	0.062	-0.119
20	L3_D13_Bias	-0.269	-0.134	-0.135
20	L3_D14_Bias	-0.237	-0.138	-0.099
20	L3_D15_Bias	-0.228	-0.126	-0.103
20	L4_D16_Bias	-0.157	0.020	-0.176
20	L4_D17_Bias	-0.197	-0.113	-0.083
20	L4_D18_Bias	-0.199	-0.049	-0.150
20	L4_D19_Bias	-1.071	-0.959	-0.112
20	L4_D20_Bias	-0.124	0.030	-0.155
30	L3_D31_Bias	-0.269	0.064	-0.333
30	L3_D32_Bias	-0.637	-0.472	-0.165
30	L3_D33_Bias	0.025	0.293	-0.268
30	L3_D34_Bias	-0.125	0.240	-0.365
30	L3_D35_Bias	-0.246	0.126	-0.372
30	L4_D36_Bias	-0.153	0.117	-0.270
30	L4_D37_Bias	-0.101	0.154	-0.255
30	L4_D38_Bias	-0.175	0.139	-0.315
30	L4_D39_Bias	-0.162	0.159	-0.322
30	L4_D40_Bias	-0.121	0.213	-0.335
	Max	0.025	0.293	0.008
	Average	-0.240	-0.047	-0.192
	Min	-1.071	-0.959	-0.372
	Std Dev	0.232	0.280	0.116

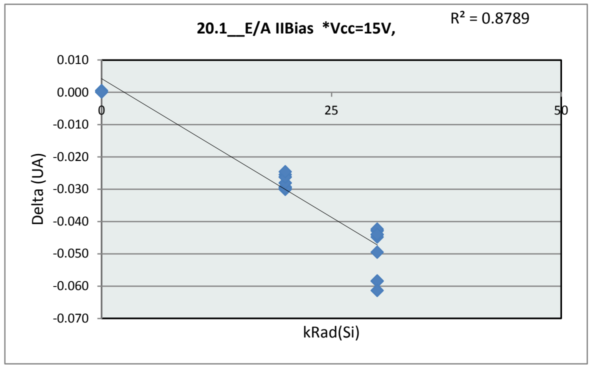


	19.1__E/A Voffset *Vcc=15V,		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	4	MV	
Min Limit	-4	MV	
kRad(Si)	0	20	30
LL	-4.000	-4.000	-4.000
Min	-0.178	-0.959	-0.472
Average	-0.145	-0.178	0.104
Max	-0.112	0.062	0.293
UL	4.000	4.000	4.000

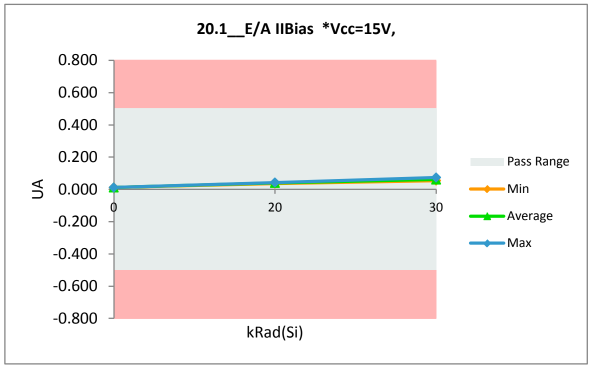


TID Report
UC19432-SP

		20.1__E/A IIBias *Vcc=15V,		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	UA	UA	
	Max Limit	0.5	0.5	
	Min Limit	-0.5	-0.5	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.012	0.012	0.000
0	L3_D84_Corr	0.012	0.012	0.000
20	L3_D11_Bias	0.012	0.040	-0.028
20	L3_D12_Bias	0.012	0.042	-0.029
20	L3_D13_Bias	0.012	0.041	-0.029
20	L3_D14_Bias	0.012	0.042	-0.030
20	L3_D15_Bias	0.011	0.041	-0.030
20	L4_D16_Bias	0.012	0.040	-0.028
20	L4_D17_Bias	0.011	0.037	-0.025
20	L4_D18_Bias	0.012	0.038	-0.026
20	L4_D19_Bias	0.012	0.038	-0.026
20	L4_D20_Bias	0.012	0.037	-0.025
30	L3_D31_Bias	0.012	0.070	-0.059
30	L3_D32_Bias	0.011	0.061	-0.050
30	L3_D33_Bias	0.012	0.056	-0.045
30	L3_D34_Bias	0.013	0.071	-0.058
30	L3_D35_Bias	0.012	0.073	-0.061
30	L4_D36_Bias	0.012	0.054	-0.043
30	L4_D37_Bias	0.013	0.057	-0.044
30	L4_D38_Bias	0.012	0.055	-0.043
30	L4_D39_Bias	0.012	0.054	-0.042
30	L4_D40_Bias	0.013	0.057	-0.044
	Max	0.013	0.073	0.000
	Average	0.012	0.047	-0.035
	Min	0.011	0.012	-0.061
	Std Dev	0.000	0.016	0.016



	20.1__E/A IIBias *Vcc=15V,		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.5	UA	
Min Limit	-0.5	UA	
kRad(Si)	0	20	30
LL	-0.500	-0.500	-0.500
Min	0.012	0.037	0.054
Average	0.012	0.040	0.061
Max	0.012	0.042	0.074
UL	0.500	0.500	0.500



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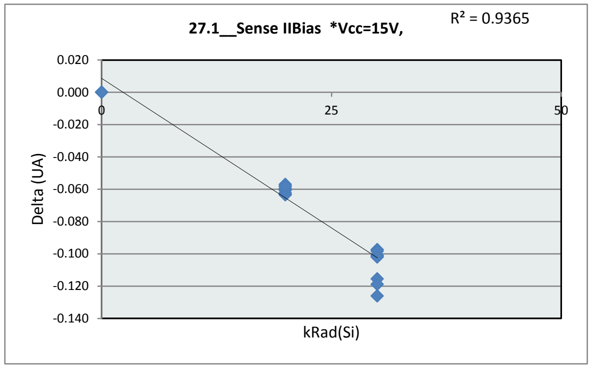
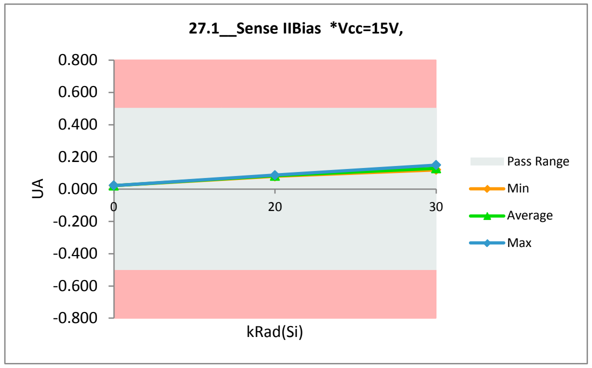
kRad(Si)	Serial #	pre_rad	post_rad	Delta
		27.1__Sense IIBias *Vcc=15V,		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	UA	UA	
	Max Limit	0.5	0.5	
	Min Limit	-0.5	-0.5	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.022	0.022	0.000
0	L3_D84_Corr	0.023	0.023	0.000
20	L3_D11_Bias	0.022	0.082	-0.060
20	L3_D12_Bias	0.023	0.086	-0.063
20	L3_D13_Bias	0.023	0.082	-0.060
20	L3_D14_Bias	0.024	0.084	-0.061
20	L3_D15_Bias	0.022	0.084	-0.062
20	L4_D16_Bias	0.024	0.087	-0.063
20	L4_D17_Bias	0.022	0.079	-0.057
20	L4_D18_Bias	0.023	0.081	-0.058
20	L4_D19_Bias	0.023	0.083	-0.060
20	L4_D20_Bias	0.023	0.081	-0.058
30	L3_D31_Bias	0.023	0.138	-0.116
30	L3_D32_Bias	0.022	0.124	-0.102
30	L3_D33_Bias	0.023	0.124	-0.101
30	L3_D34_Bias	0.023	0.142	-0.119
30	L3_D35_Bias	0.023	0.149	-0.126
30	L4_D36_Bias	0.022	0.120	-0.097
30	L4_D37_Bias	0.023	0.124	-0.101
30	L4_D38_Bias	0.024	0.122	-0.098
30	L4_D39_Bias	0.023	0.122	-0.098
30	L4_D40_Bias	0.024	0.126	-0.102
	Max	0.024	0.149	0.000
	Average	0.023	0.098	-0.076
	Min	0.022	0.022	-0.126
	Std Dev	0.001	0.034	0.034



	27.1__Sense IIBias *Vcc=15V		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.5	UA	
Min Limit	-0.5	UA	
kRad(Si)	0	20	30
LL	-0.500	-0.500	-0.500
Min	0.022	0.079	0.120
Average	0.022	0.083	0.129
Max	0.023	0.087	0.149
UL	0.500	0.500	0.500



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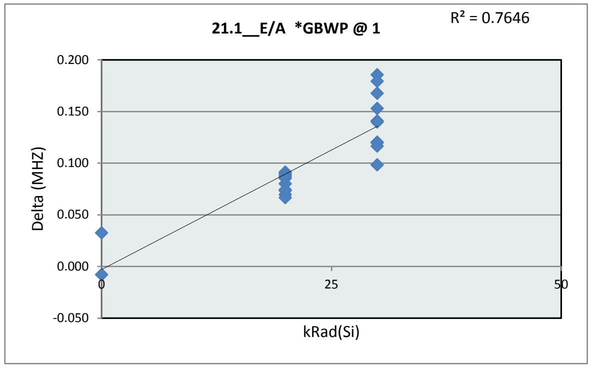
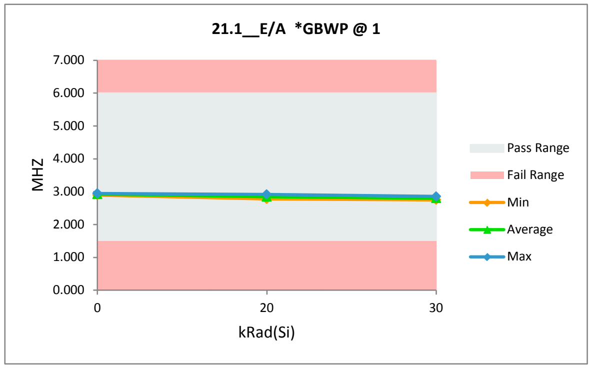
		21.1__E/A *GBWP @ 1		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MHZ	MHZ	
	Max Limit	6	6	
	Min Limit	1.5	1.5	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	2.981	2.948	0.033
0	L3_D84_Corr	2.890	2.898	-0.008
20	L3_D11_Bias	2.920	2.851	0.070
20	L3_D12_Bias	2.990	2.899	0.090
20	L3_D13_Bias	2.985	2.905	0.080
20	L3_D14_Bias	2.986	2.913	0.073
20	L3_D15_Bias	2.964	2.873	0.091
20	L4_D16_Bias	2.877	2.810	0.067
20	L4_D17_Bias	2.871	2.782	0.089
20	L4_D18_Bias	2.889	2.804	0.085
20	L4_D19_Bias	2.865	2.779	0.087
20	L4_D20_Bias	2.907	2.832	0.074
30	L3_D31_Bias	2.970	2.785	0.185
30	L3_D32_Bias	2.946	2.793	0.153
30	L3_D33_Bias	2.983	2.842	0.141
30	L3_D34_Bias	3.020	2.853	0.168
30	L3_D35_Bias	3.016	2.836	0.179
30	L4_D36_Bias	2.923	2.804	0.120
30	L4_D37_Bias	2.872	2.752	0.120
30	L4_D38_Bias	2.909	2.793	0.116
30	L4_D39_Bias	2.911	2.772	0.140
30	L4_D40_Bias	2.861	2.763	0.098
	Max	3.020	2.948	0.185
	Average	2.933	2.831	0.102
	Min	2.861	2.752	-0.008
	Std Dev	0.052	0.055	0.047



	21.1__E/A *GBWP @ 1		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	6	MHZ	
Min Limit	1.5	MHZ	
kRad(Si)	0	20	30
LL	1.500	1.500	1.500
Min	2.898	2.779	2.752
Average	2.923	2.845	2.799
Max	2.948	2.913	2.853
UL	6.000	6.000	6.000



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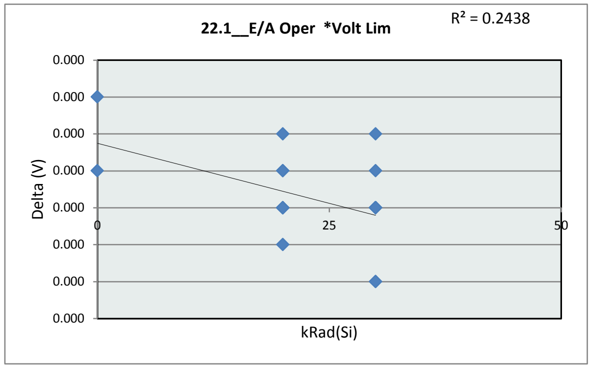
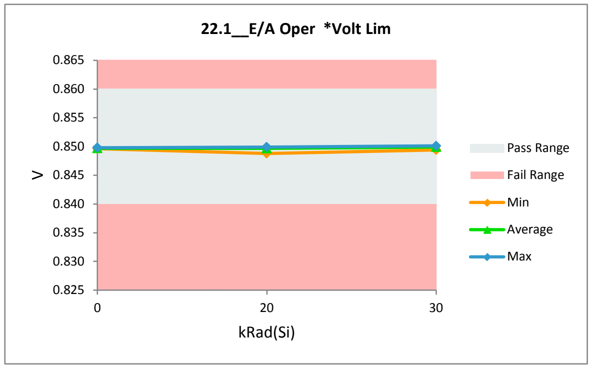
		22.1__E/A Oper *Volt Lim		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	V	V	
	Max Limit	0.86	0.86	
	Min Limit	0.84	0.84	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.850	0.850	0.000
0	L3_D84_Corr	0.850	0.850	0.000
20	L3_D11_Bias	0.850	0.850	0.000
20	L3_D12_Bias	0.850	0.850	0.000
20	L3_D13_Bias	0.850	0.850	0.000
20	L3_D14_Bias	0.850	0.850	0.000
20	L3_D15_Bias	0.850	0.850	0.000
20	L4_D16_Bias	0.850	0.850	0.000
20	L4_D17_Bias	0.850	0.850	0.000
20	L4_D18_Bias	0.850	0.850	0.000
20	L4_D19_Bias	0.849	0.849	0.000
20	L4_D20_Bias	0.850	0.850	0.000
30	L3_D31_Bias	0.850	0.850	0.000
30	L3_D32_Bias	0.850	0.849	0.000
30	L3_D33_Bias	0.850	0.850	0.000
30	L3_D34_Bias	0.850	0.850	0.000
30	L3_D35_Bias	0.850	0.850	0.000
30	L4_D36_Bias	0.850	0.850	0.000
30	L4_D37_Bias	0.850	0.850	0.000
30	L4_D38_Bias	0.850	0.850	0.000
30	L4_D39_Bias	0.850	0.850	0.000
30	L4_D40_Bias	0.850	0.850	0.000
	Max	0.850	0.850	0.000
	Average	0.850	0.850	0.000
	Min	0.849	0.849	0.000
	Std Dev	0.000	0.000	0.000



	22.1__E/A Oper *Volt Lim		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.86	V	
Min Limit	0.84	V	
kRad(Si)	0	20	30
LL	0.840	0.840	0.840
Min	0.850	0.849	0.849
Average	0.850	0.850	0.850
Max	0.850	0.850	0.850
UL	0.860	0.860	0.860



TID Report
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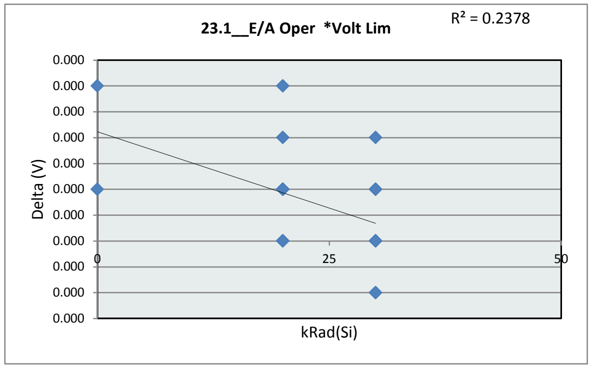
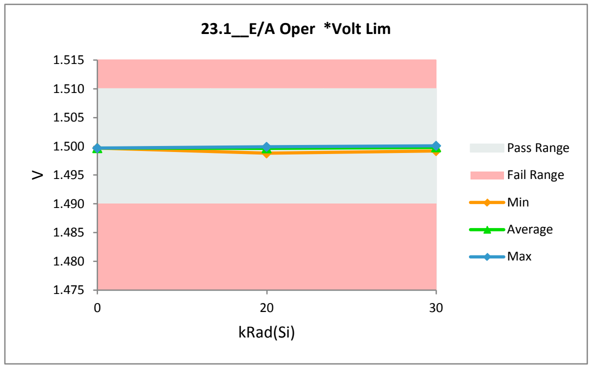
		23.1__E/A Oper *Volt Lim		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	V	V	
	Max Limit	1.51	1.51	
	Min Limit	1.49	1.49	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	1.500	1.500	0.000
0	L3_D84_Corr	1.500	1.500	0.000
20	L3_D11_Bias	1.500	1.500	0.000
20	L3_D12_Bias	1.500	1.500	0.000
20	L3_D13_Bias	1.500	1.500	0.000
20	L3_D14_Bias	1.500	1.500	0.000
20	L3_D15_Bias	1.500	1.500	0.000
20	L4_D16_Bias	1.500	1.500	0.000
20	L4_D17_Bias	1.500	1.500	0.000
20	L4_D18_Bias	1.500	1.500	0.000
20	L4_D19_Bias	1.499	1.499	0.000
20	L4_D20_Bias	1.500	1.500	0.000
30	L3_D31_Bias	1.500	1.500	0.000
30	L3_D32_Bias	1.499	1.499	0.000
30	L3_D33_Bias	1.500	1.500	0.000
30	L3_D34_Bias	1.500	1.500	0.000
30	L3_D35_Bias	1.500	1.500	0.000
30	L4_D36_Bias	1.500	1.500	0.000
30	L4_D37_Bias	1.500	1.500	0.000
30	L4_D38_Bias	1.500	1.500	0.000
30	L4_D39_Bias	1.500	1.500	0.000
30	L4_D40_Bias	1.500	1.500	0.000
	Max	1.500	1.500	0.000
	Average	1.500	1.500	0.000
	Min	1.499	1.499	0.000
	Std Dev	0.000	0.000	0.000



	23.1__E/A Oper *Volt Lim		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	1.51	V	
Min Limit	1.49	V	
kRad(Si)	0	20	30
LL	1.490	1.490	1.490
Min	1.500	1.499	1.499
Average	1.500	1.500	1.500
Max	1.500	1.500	1.500
UL	1.510	1.510	1.510



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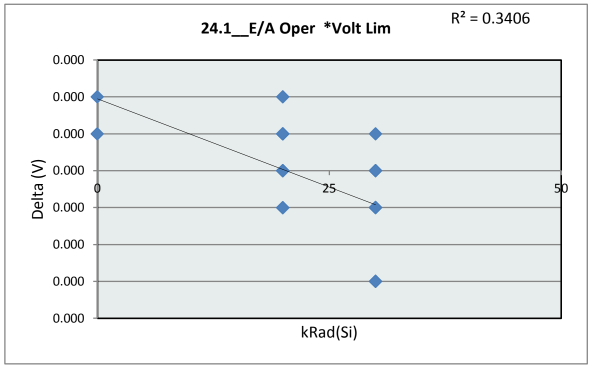
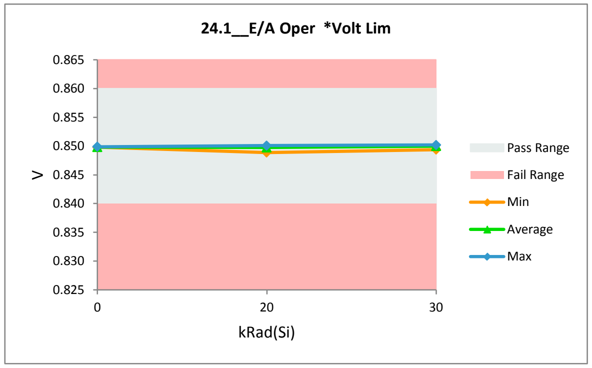
	24.1__E/A Oper *Volt Lim	
Test Site	Sherman TX	Sherman TX
Tester	Eagle	Eagle
Test Number	EF266101	EF266101
Unit	V	V
Max Limit	0.86	0.86
Min Limit	0.84	0.84

kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	0.850	0.850	0.000
0	L3_D84_Corr	0.850	0.850	0.000
20	L3_D11_Bias	0.850	0.850	0.000
20	L3_D12_Bias	0.850	0.850	0.000
20	L3_D13_Bias	0.850	0.850	0.000
20	L3_D14_Bias	0.850	0.850	0.000
20	L3_D15_Bias	0.850	0.850	0.000
20	L4_D16_Bias	0.850	0.850	0.000
20	L4_D17_Bias	0.850	0.850	0.000
20	L4_D18_Bias	0.850	0.850	0.000
20	L4_D19_Bias	0.849	0.849	0.000
20	L4_D20_Bias	0.850	0.850	0.000
30	L3_D31_Bias	0.850	0.850	0.000
30	L3_D32_Bias	0.850	0.849	0.000
30	L3_D33_Bias	0.850	0.850	0.000
30	L3_D34_Bias	0.850	0.850	0.000
30	L3_D35_Bias	0.850	0.850	0.000
30	L4_D36_Bias	0.850	0.850	0.000
30	L4_D37_Bias	0.850	0.850	0.000
30	L4_D38_Bias	0.850	0.850	0.000
30	L4_D39_Bias	0.850	0.850	0.000
30	L4_D40_Bias	0.850	0.850	0.000
	Max	0.850	0.850	0.000
	Average	0.850	0.850	0.000
	Min	0.849	0.849	0.000
	Std Dev	0.000	0.000	0.000



	24.1__E/A Oper *Volt Lim		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	0.86	V	
Min Limit	0.84	V	
kRad(Si)	0	20	30
LL	0.840	0.840	0.840
Min	0.850	0.849	0.849
Average	0.850	0.850	0.850
Max	0.850	0.850	0.850
UL	0.860	0.860	0.860



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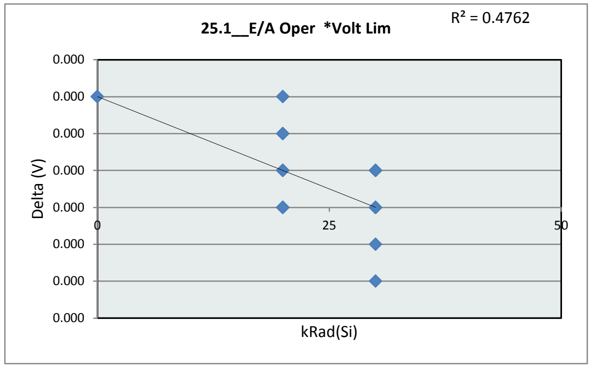
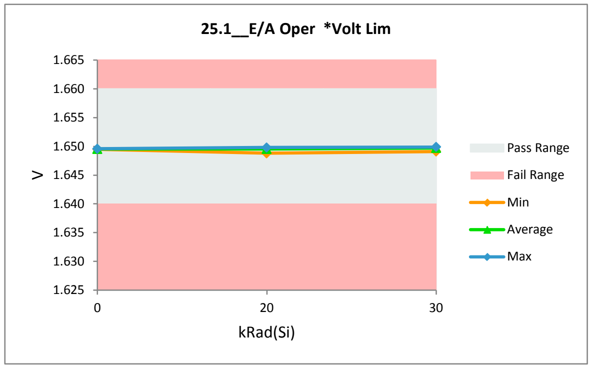
		25.1__E/A Oper *Volt Lim		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	V	V	
	Max Limit	1.66	1.66	
	Min Limit	1.64	1.64	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	1.650	1.650	0.000
0	L3_D84_Corr	1.650	1.650	0.000
20	L3_D11_Bias	1.649	1.649	0.000
20	L3_D12_Bias	1.650	1.650	0.000
20	L3_D13_Bias	1.650	1.650	0.000
20	L3_D14_Bias	1.650	1.650	0.000
20	L3_D15_Bias	1.650	1.650	0.000
20	L4_D16_Bias	1.650	1.650	0.000
20	L4_D17_Bias	1.650	1.650	0.000
20	L4_D18_Bias	1.650	1.650	0.000
20	L4_D19_Bias	1.649	1.649	0.000
20	L4_D20_Bias	1.650	1.650	0.000
30	L3_D31_Bias	1.650	1.650	0.000
30	L3_D32_Bias	1.649	1.649	0.000
30	L3_D33_Bias	1.650	1.650	0.000
30	L3_D34_Bias	1.650	1.650	0.000
30	L3_D35_Bias	1.650	1.650	0.000
30	L4_D36_Bias	1.650	1.650	0.000
30	L4_D37_Bias	1.650	1.650	0.000
30	L4_D38_Bias	1.650	1.650	0.000
30	L4_D39_Bias	1.650	1.650	0.000
30	L4_D40_Bias	1.650	1.650	0.000
	Max	1.650	1.650	0.000
	Average	1.650	1.650	0.000
	Min	1.649	1.649	0.000
	Std Dev	0.000	0.000	0.000

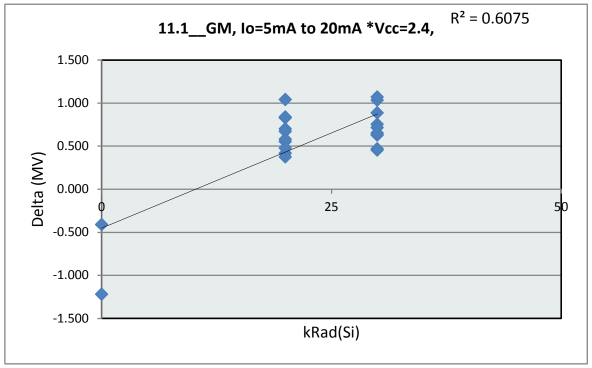


	25.1__E/A Oper *Volt Lim		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	1.66	V	
Min Limit	1.64	V	
kRad(Si)	0	20	30
LL	1.640	1.640	1.640
Min	1.650	1.649	1.649
Average	1.650	1.650	1.650
Max	1.650	1.650	1.650
UL	1.660	1.660	1.660

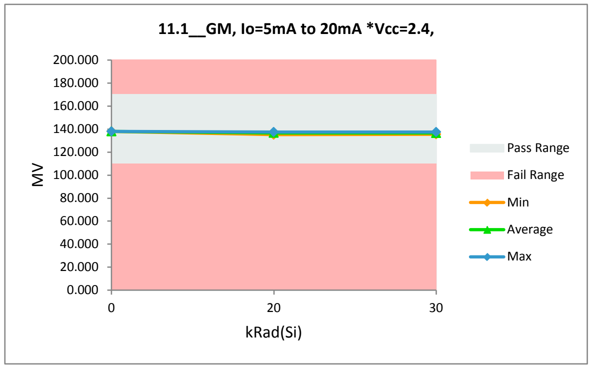


TID Report
UC19432-SP

		11.1__GM, Io=5mA to 20mA *Vc		
	Test Site	Sherman TX	Sherman TX	
	Tester	Eagle	Eagle	
	Test Number	EF266101	EF266101	
	Unit	MV	MV	
	Max Limit	170	170	
	Min Limit	110	110	
kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	136.848	138.066	-1.219
0	L3_D84_Corr	137.731	138.141	-0.410
20	L3_D11_Bias	136.313	135.273	1.041
20	L3_D12_Bias	137.904	137.351	0.553
20	L3_D13_Bias	138.376	137.548	0.828
20	L3_D14_Bias	137.855	137.155	0.700
20	L3_D15_Bias	137.239	136.401	0.838
20	L4_D16_Bias	137.607	136.935	0.672
20	L4_D17_Bias	136.217	135.798	0.418
20	L4_D18_Bias	136.970	136.594	0.375
20	L4_D19_Bias	138.102	137.523	0.579
20	L4_D20_Bias	137.632	137.155	0.477
30	L3_D31_Bias	137.337	136.304	1.033
30	L3_D32_Bias	136.192	135.559	0.634
30	L3_D33_Bias	137.239	136.352	0.886
30	L3_D34_Bias	138.227	137.474	0.753
30	L3_D35_Bias	138.077	137.008	1.069
30	L4_D36_Bias	137.756	137.302	0.454
30	L4_D37_Bias	137.018	136.304	0.715
30	L4_D38_Bias	136.386	135.918	0.468
30	L4_D39_Bias	138.077	137.449	0.628
30	L4_D40_Bias	137.929	137.277	0.651
	Max	138.376	138.141	1.069
	Average	137.411	136.859	0.552
	Min	136.192	135.273	-1.219
	Std Dev	0.686	0.785	0.501



	11.1__GM, Io=5mA to 20mA *		
Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	170	MV	
Min Limit	110	MV	
kRad(Si)	0	20	30
LL	110.000	110.000	110.000
Min	138.066	135.273	135.559
Average	138.104	136.773	136.695
Max	138.141	137.548	137.474
UL	170.000	170.000	170.000

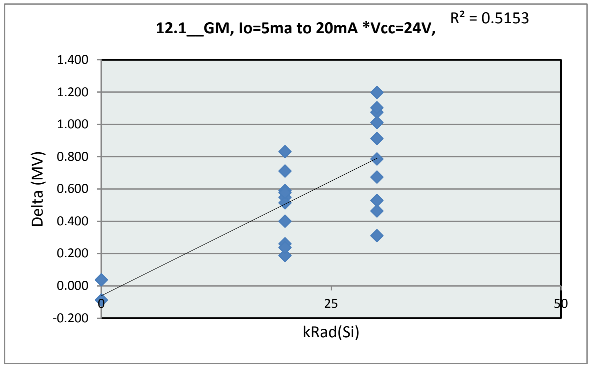


TID Report
UC19432-SP

12.1__GM, Io=5ma to 20mA *Vc

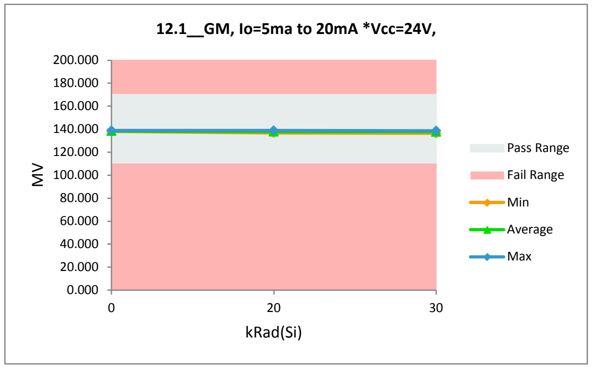
Test Site		Sherman TX	Sherman TX
Tester		Eagle	Eagle
Test Number		EF266101	EF266101
Unit		MV	MV
Max Limit		170	170
Min Limit		110	110

kRad(Si)	Serial #	pre_rad	post_rad	Delta
0	L3_D83_Corr	138.028	138.116	-0.088
0	L3_D84_Corr	138.826	138.789	0.037
20	L3_D11_Bias	137.312	136.765	0.548
20	L3_D12_Bias	139.052	138.539	0.513
20	L3_D13_Bias	139.254	138.664	0.590
20	L3_D14_Bias	138.927	138.215	0.711
20	L3_D15_Bias	138.551	137.720	0.831
20	L4_D16_Bias	138.451	138.191	0.260
20	L4_D17_Bias	137.165	136.765	0.401
20	L4_D18_Bias	137.879	137.302	0.577
20	L4_D19_Bias	139.027	138.839	0.188
20	L4_D20_Bias	138.576	138.340	0.236
30	L3_D31_Bias	138.426	137.351	1.075
30	L3_D32_Bias	137.460	136.449	1.011
30	L3_D33_Bias	138.576	137.474	1.102
30	L3_D34_Bias	139.786	138.589	1.197
30	L3_D35_Bias	139.103	138.191	0.912
30	L4_D36_Bias	138.501	138.191	0.310
30	L4_D37_Bias	137.929	137.400	0.529
30	L4_D38_Bias	137.706	137.033	0.673
30	L4_D39_Bias	138.977	138.514	0.463
30	L4_D40_Bias	138.927	138.141	0.786
	Max	139.786	138.839	1.197
	Average	138.474	137.890	0.585
	Min	137.165	136.449	-0.088
	Std Dev	0.680	0.715	0.350



12.1__GM, Io=5ma to 20mA *V

Test Site	Sherman TX		
Tester	Eagle		
Test Number	EF266101		
Max Limit	170	MV	
Min Limit	110	MV	
kRad(Si)	0	20	30
LL	110.000	110.000	110.000
Min	138.116	136.765	136.449
Average	138.453	137.934	137.733
Max	138.789	138.839	138.589
UL	170.000	170.000	170.000



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